Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/722,263	LEE ET AL.	
Examiner	Art Unit	
Jezia Rilev	1637	

	SEARCHED		
Class	Subclass	Date	Examiner
424	78.17		
530	300, 350	3/21/2005	JR
	_		
		_	
			_
_	_		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		

SEARCH (INCLUDING SEAR		Y)
	DATE	EXMR
review parent 09/547,008 and 09/982,765	3/21/2005	JR
STN search enclosed	3/21/2005	JR